

BASTION : board and SoC test instrumentation for ageing and no failure found

Jutman, Artur; Lotz, Christophe; Larsson, Erik; Sonza Reorda, Matteo; **Jenihhin, Maksim**; **Raik, Jaan** Proceedings of the 2017 Design, Automation & Test in Europe (DATE) : 27-31 March 2017, Swisstech, Lausanne, Switzerland 2017 / p. 115-120 : ill <https://doi.org/10.23919/DATE.2017.7926968>

Health management for self-aware SoCs based on IEEE 1687 infrastructure

Shibin, Konstantin; **Devadze, Sergei**; Jutman, Artur; Grabmann, Martin; Pricken, Robin IEEE Design & Test 2017 / p. 27-35 : ill <https://doi.org/10.1109/MDAT.2017.2750902> Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

IEEE P1687 IJTAG demonstrator on FPGA

Shibin, Konstantin; **Aleksejev, Igor**; **Jutman, Artur**; **Devadze, Sergei** DATE 2012 University Booth : Design Automation and Test in Europe : Dresden, Germany, March 12-16, 2012 2012 / 1 p. : ill https://www.academia.edu/22101517/IEEE_P1687_IJTAG_demonstrator_on_FPGA

Invited paper: System-Wide Fault Management based on IEEE P1687 IJTAG

Jutman, Artur; **Devadze, Sergei**; **Aleksejev, Jevgeni** 6th International Workshop on Reconfigurable Communication-centric Systems-on-Chip (ReCoSoC) : 20-22 June 2011, Montpellier, France 2011 / [4] p.: ill <https://ieeexplore.ieee.org/document/5981520>

Post-silicon validation of IEEE 1687 reconfigurable scan networks

Damljanovic, Aleksa; **Jutman, Artur**; Squillero, Giovanni; **Tšertov, Anton** 2019 IEEE European Test Symposium (ETS) : proceedings 2019 / 6 p. : ill <https://doi.org/10.1109/ETS.2019.8791546>

Reliable health monitoring and fault management infrastructure based on embedded instrumentation and IEEE 1687

Jutman, Artur; **Shibin, Konstantin**; **Devadze, Sergei** IEEE AUTOTESTCON 2016 : Anaheim, California, USA, September 12-15, 2016 : proceedings 2016 / p. 240-249 : ill <https://doi.org/10.1109/AUTEST.2016.7589605>

Simulation-based equivalence checking between IEEE 1687 ICL and RTL

Damljanovic, Aleksa; **Jutman, Artur**; Portolan, Michele; Tšertov, Anton 2019 IEEE International Test Conference (ITC) 2019 / paper. 7.3, 8 p. : ill <https://doi.org/10.1109/ITC44170.2019.9000181>

A suite of IEEE 1687 benchmark networks

Tšertov, Anton; **Jutman, Artur**; **Devadze, Sergei** 2016 IEEE International Test Conference (ITC) : proceedings 2016 / art. 6.1, p. 1-10 : ill <https://doi.org/10.1109/TEST.2016.7805840>

System-wide fault management based on IEEE P1687 IJTAG

Shibin, Konstantin; **Jutman, Artur**; **Devadze, Sergei** Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK kuuenda aastakonverentsi artiklite kogumik : 3.-5. oktoobril 2012, Laulasmaa 2012 / p. 81-84 : ill